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| Substitute Form PTO-1449 (Modified) | U.S. Department of Commerce Patent and Trademark Office | Attorney's Docket No. 12732-207001 | Application No. <i>10/756 756</i> New Application |
| Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b)) | | Applicant Hajime Kimura et al. | |
| | | Filing Date January 14, 2004 | Group Art Unit <i>2673</i> |

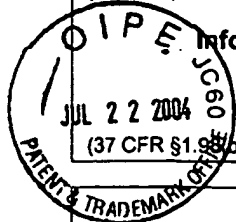
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| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
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| | | | | | | | Yes | No |
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| Examiner Signature <i>Jeff Piziali</i> | Date Considered <i>6-20-2005</i> |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |

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| | | Filing Date January 14, 2004 | Group Art Unit 2673 |



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| Examiner Signature <i>Jeff Piziali</i> | Date Considered <i>6-20-05</i> |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |